

Use of polyvinylpyrrolidone in the LiNbO₃ thin films deposition

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Lithium niobate belongs to the group of the most important crystalline materials. This ferroelectric material with the Currie temperature of 1150 °C is mostly used in acousto-optic devices, optical waveguides, nonlinear optics and pyroelectric sensors. Its applications are extended using rare earth ions doping. LiNbO₃ is prepared in the form of monocrystals, optical fibers or thin films. The thin films are produced by various methods – e.g. ion implantation, liquid phase epitaxy (LPE), pulsed laser deposition (PLD), molecular beam epitaxy (MBE), chemical vapor deposition (CVD), physical vapor deposition (PVD) or a sol-gel technique. Due to the Er³⁺ ion luminescence, the doped LiNbO₃ can be used in the IR region for the amplification of optical signal in the third telecommunication window (1525 nm). The co-doping of Er³⁺ and Yb³⁺ ions increases the intensity of the Er³⁺ luminescence due to energy transfer between the excited states of both ions.

This work presents the preparation of LiNbO₃ thin layers doped with 0.5 at % of Er³⁺ and 0.5 at % of Yb³⁺. The layers were deposited on a sapphire (0001) substrate by spin-coating. Used solutions were prepared by a non-aqueous sol-gel method using a 2-methoxyethoxide solution of present cations and polyvinylpyrrolidone (PVP). The influence of different PVP molar mass (29 000 or 360 000 g/mol) on the final microstructure was tested. Then the effect of different annealing of the deposited films (one- or two-step) was examined. Its influence on the film crystallinity, on the Er³⁺/Yb³⁺: LiNbO₃ luminescence and waveguiding properties was investigated. The thin films were characterized by the photoluminescence and transmittance spectroscopy, m-line spectroscopy, X-ray diffraction analysis, scanning electron microscopy, atomic force microscopy and thickness measurement.

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